

# Abstracts

## Improved Calibration and Measurement of the Scattering Parameters of Microwave Integrated Circuits (Comments and Reply)

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*R. Marks, R.R. Pantoja, M.J. Howes, J.R. Richardson and R.D. Pollard. "Improved Calibration and Measurement of the Scattering Parameters of Microwave Integrated Circuits (Comments and Reply)." 1990 Transactions on Microwave Theory and Techniques 38.4 (Apr. 1990 [T-MTT]): 453-454.*

The above paper proposes "generalized TRL" as an alternative to the TRL and LRL calibration methods. The contributions of the work, according to the authors, are "the reformulation in terms of S parameters and the removal of the requirement to specify a line length." In fact, it appears that only the formulation, not the method itself, is novel.

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